

Listing of Claims

This listing of claims will replace all prior versions and listings of claims in the application:

Claims 1-4 (Canceled).

Claim 5 (Currently Amended) ~~The inspection method according to claim 4~~ A method of inspecting a target object to be inspected, comprising the steps of:

bringing about a fritting phenomenon using at least one probe in a part of the insulating film formed on an inspection electrode of the target object to be inspected so as to break a part of the insulating film;

bringing the at least one probe, used to bring about the fritting phenomenon, into electrical contact with the surface of a part of the inspection electrode, the insulating film of the part of the inspection electrode having been broken by the fritting phenomenon; and

inspecting the electrical characteristics of the target object by using a tester connected to the at least one probe,

wherein said step of inspecting the electrical characteristics of the target object to be inspected by utilizing the at least one probe further comprises the step of electrically disconnecting the second probe not being used for inspecting from at least one of the tester and the inspection electrode.

Claim 6 (Currently Amended): ~~The inspection method according to claim 3,~~ A method of inspecting a target object to be inspected, comprising the steps of:

bringing about a fritting phenomenon using at least one probe in a part of the insulating film formed on an inspection electrode of the target object to be inspected so as to break a part of the insulating film;

bringing the at least one probe, used to bring about the fritting phenomenon, into electrical contact with the surface of a part of the inspection electrode, the insulating film of the part of the inspection electrode having been broken by the fritting phenomenon; and

inspecting the electrical characteristics of the target object by using a tester connected to the at least one probe,

wherein said step of breaking a part of the insulating film comprises the steps of:

bringing the at least one probe and a second probe into contact with the inspection electrode of the target object; and

applying a voltage between the at least one probe and the second probe so as to bring about the fritting phenomenon in the insulating film formed on the surface of the inspection electrode, and

wherein said step of inspecting the electrical characteristics of the target object to be inspected by utilizing the at least one probe further includes electrically disconnecting the second probe from the inspection electrode comprises the step of electrically by physically separating the second probe from the inspection electrode.

Appl. No. 09/931,888

Reply to Office Action of December 18, 2003

Claim 7 (Previously Presented): The inspection method according to claim 6, wherein said physically separating step is performed by utilizing at least one of a piezo element, a bimetal, and an electrostatic element.

Claims 8-15 (Canceled).